

Detection Technologies for Cryo-Electron Microscopy

S²C² Workshop – Cryo-EM Training for Beginners

Christopher Booth

Gatan Inc.

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Key Concepts in Detecting Electrons

Key Concepts in Detecting Electrons

- CMOS and CCD
- “indirect” vs direct detection cameras
- Sensitivity
- Linearity and dynamic range
- Dynamic range
- Pixel size and field of view
- Electron counting
- Co-incidence loss



Recording Images In Electron Microscopy

A little bit of history

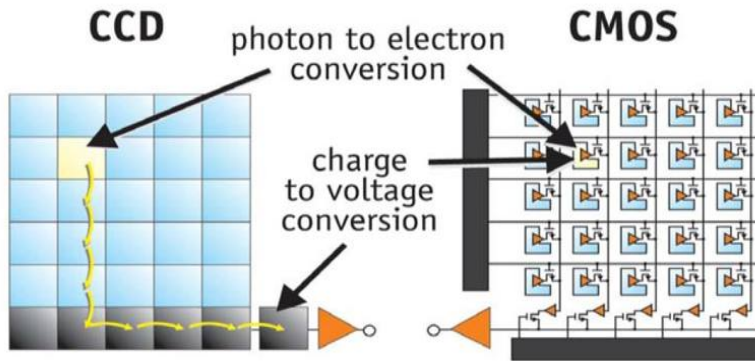
- Oldest recording medium: photographic film
- 1970: Charge coupled device (CCD) was invented
- 1976: CCD camera was used for astronomy
- 1982: 100 x 100 CCD was *directly* exposed to 100 kV electrons...radiation damage
- 1988: 576 x 382 CCD used with scintillator and optical coupler
- 1990: **Gatan** made the world's first commercial CCD camera
- 2002: 128 x 128 direct detection camera developed
- 2008 – 2009: commercial complementary metal-oxide semiconductor (CMOS) cameras and radiation hard CMOS cameras were introduced



CCD vs. CMOS

Both CCD and CMOS use photo diodes to convert photons to electrons, the difference is how they store charge and transfer it.

- **CCD**: Charge is transferred between neighboring cells, and read-out
- **CMOS** : Charge immediately converted to voltage (read out with digital output)



CCDs move photogenerated charge from pixel to pixel and convert it to voltage at an output node. CMOS imagers convert charge to voltage inside each pixel.

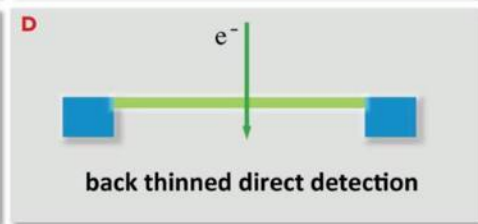
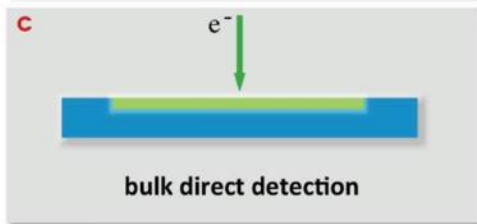
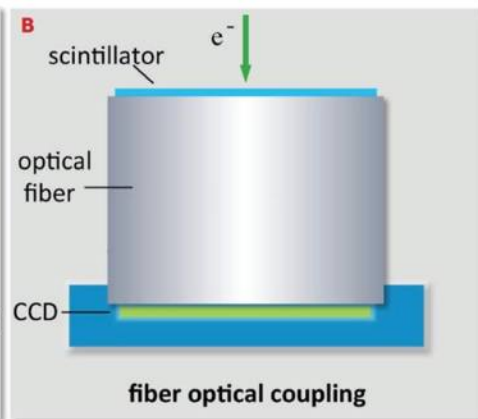
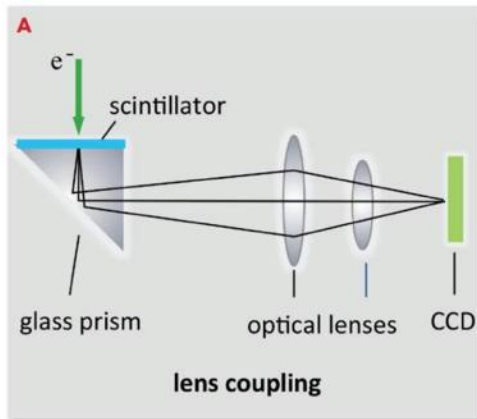
Detectors in Electron Microscopy

A. Optically coupled

B. Fiber-optic coupling

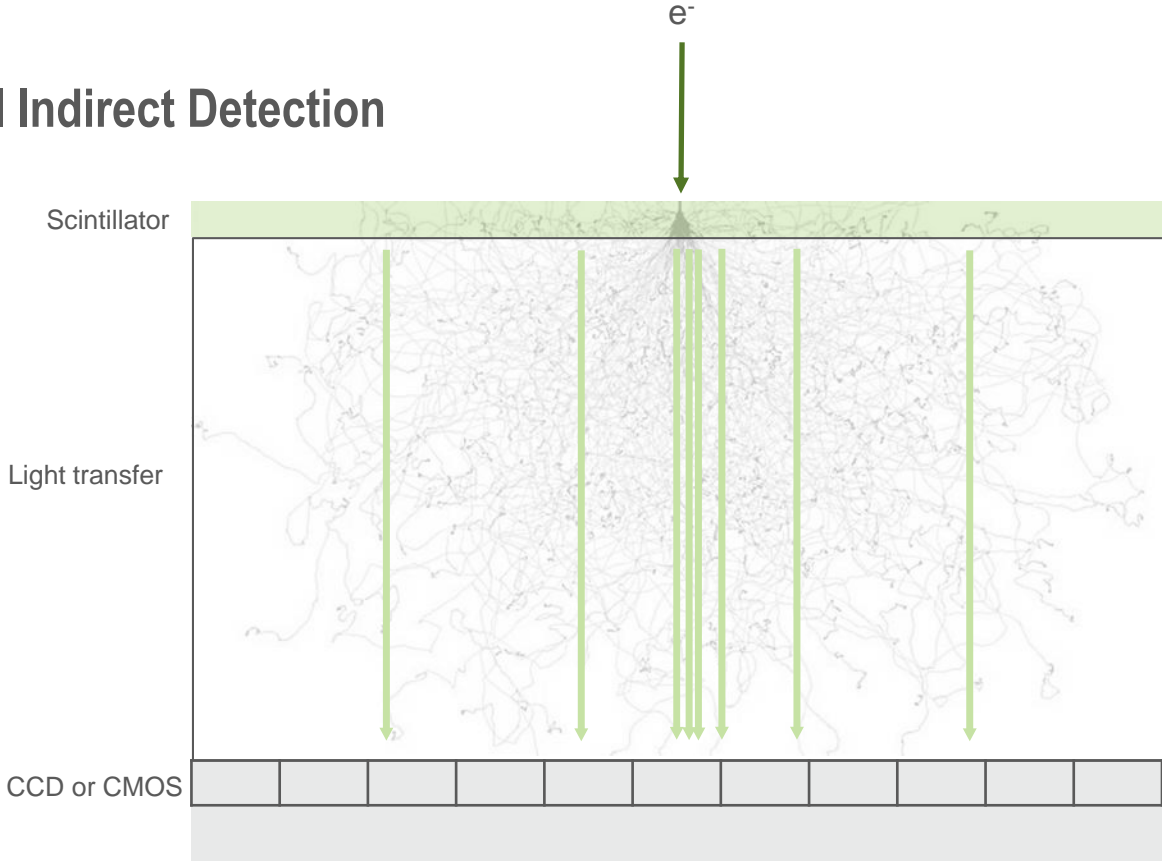
C. Direct detection

D. Transmission direct detection



Traditional Indirect Detection

1. Convert electrons to light
2. Transfer light to detector
3. Detect light and convert to signal



Light sensitive CCD or CMOS

Direct Detection

1. Convert electrons to light
2. Transfer light to detector
3. Detect electron and convert to signal

e^-



Radiation hard CMOS



Transmission Direct Detection

1. Convert electrons to light
2. Transfer light to detector
3. Detect electron and convert to signal



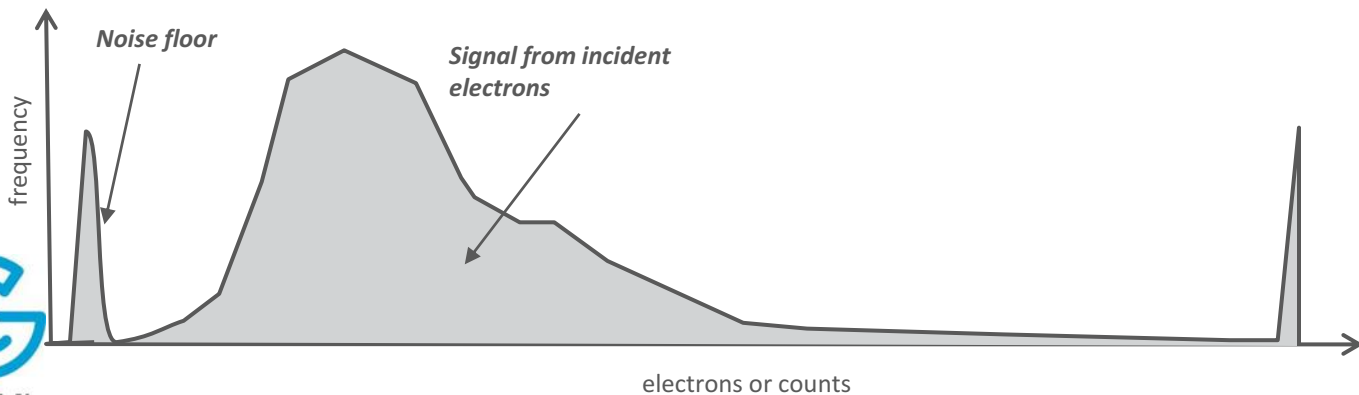
Radiation hard, thinned CMOS



Minimize back scattered electrons that add noise

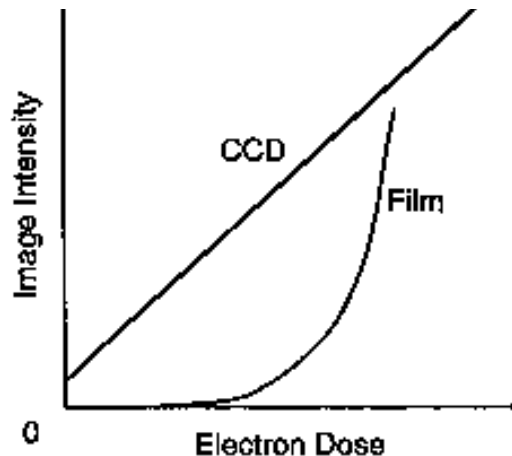
Sensitivity

- Minimum detectable signal in terms of the number of incident electrons.
- Single-electron sensitivity
 - if the gain of the system is such that the output of a single incident electron is above the noise floor



Linearity

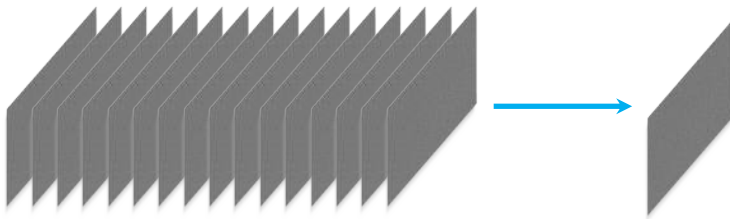
- Relationship between output (image intensity in digital units) and the input (number of incident electrons).
- CMOS and CCDS are much more linear than film
- Counted cameras have a special kind of non-linearity called co-incidence loss



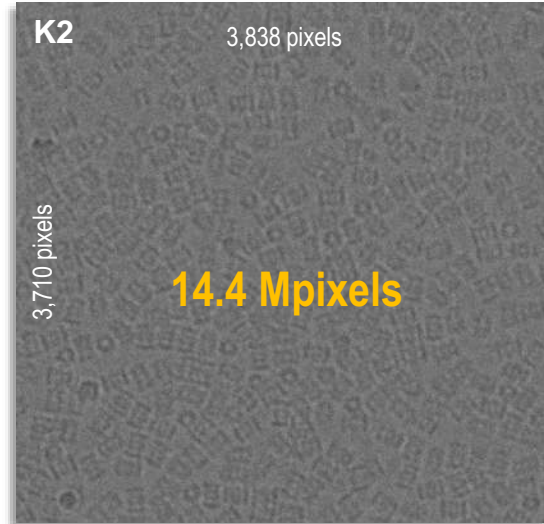
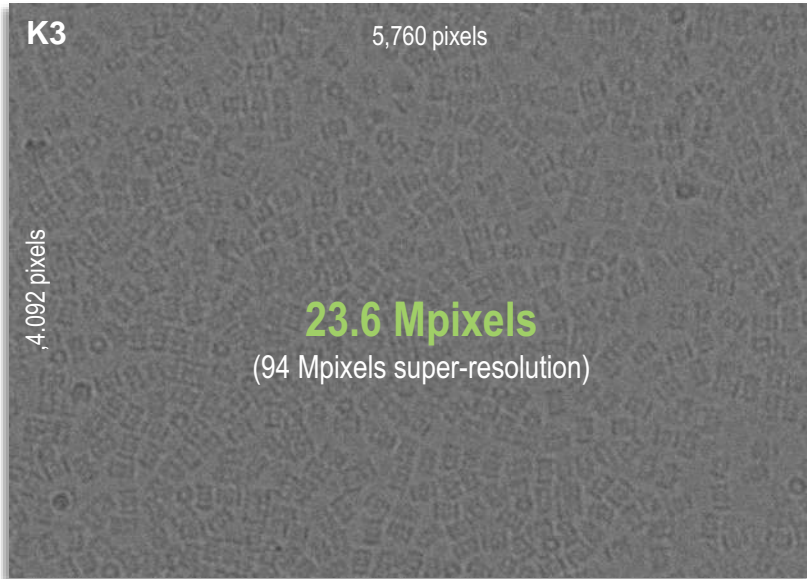
Dynamic Range

Dynamic range: The range of values that can be distinguished between a maximum level (saturation) and zero (noise)

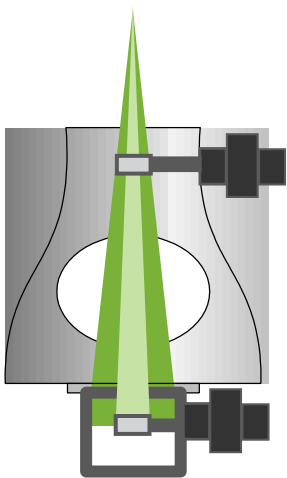
- Driven by combination of max allowable charge in each and noise floor
 - One pixel can have 16 bit dynamic range (values between 0 – 16000)
- Used to be a very important factor for cameras, now frame rate is much more important
 - A camera with only 12 bit dynamic range (0 – 4095) might accumulate 40 frames in a second.
 - $4095 \times 20 = 163,800$ counts of dynamic range



How Many Pixels are Enough?



How Important is FOV?

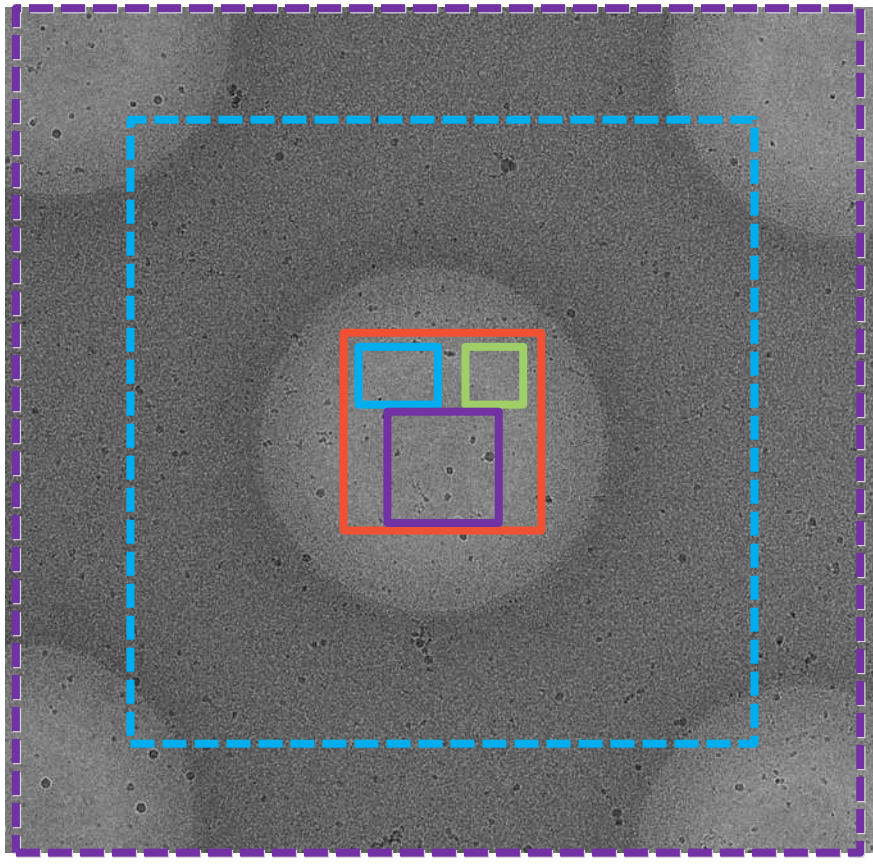


Side-mount camera

- Rio™ 16: 4k x 4k, 9 μm
- Rio 9: 3k x 3k, 9 μm

Bottom-mount camera

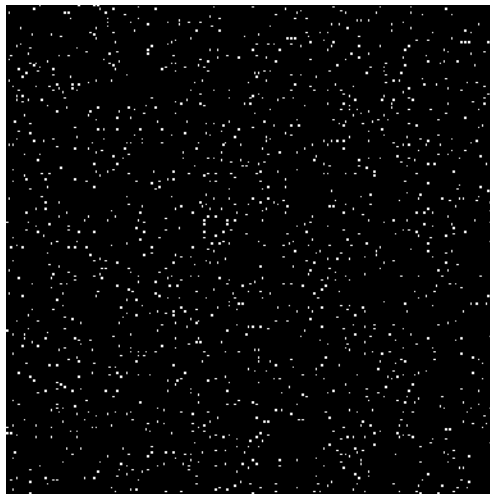
- OneView®: 4k x 4k, 15 μm
- Rio 16: 4k x 4k, 9 μm
- K3™ : 6k x 4k, 5 μm
- K2®: 4k x 4k, 5 μm



Electron Counting Makes All the Difference



Single high speed frame using conventional
CCD-style charge read-out

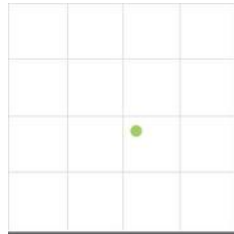


Same frame after counting

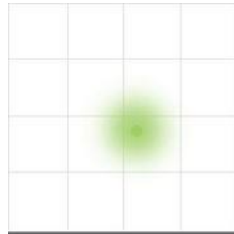
Counting removes the variability from scattering,
rejects the electronic read-noise, and restores the DQE.

Traditional Integration

Similar to indirect detection cameras, direct detectors can integrate the total charge produced when an electron strikes a pixel.



Electron enters
Detector.



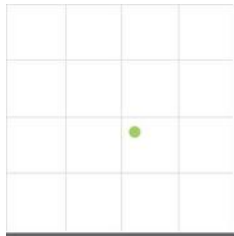
Electron signal is
scattered.



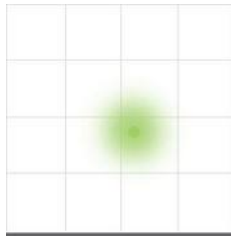
Charge collects in
each pixel.

Counting

In counting mode, individual electron events are identified at the time that they reach the detector. To do this efficiently the camera must run fast enough so that individual electron events can be identified separately.



Electron enters
Detector.



Electron signal is
scattered.



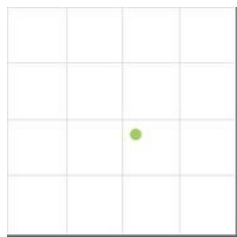
Charge collects in
each pixel.



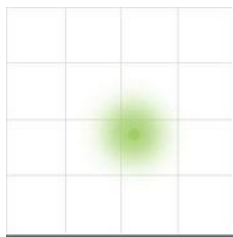
Event reduced to
highest charge pixels.

Super-Resolution

The theoretical information limit defined by the physical pixel size is surpassed when you use the K2 in super-resolution mode. The K2 sensor pixel size is slightly smaller than the area that the electron interacts with; as a result each incoming electron deposits signal in a small cluster of pixels. High-speed electronics are able to recognize each electron event (at 400 fps) and find the center of event with sub-pixel precision.



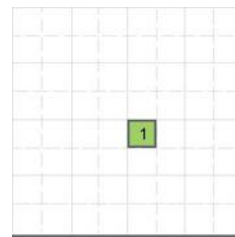
Electron enters
Detector.



Electron signal is
scattered.

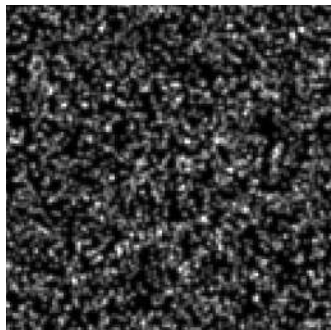


Charge collects in
each pixel.

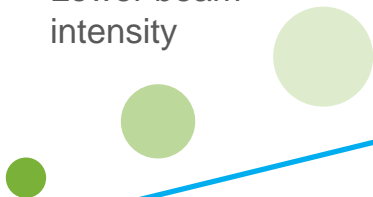


Event localized to
sub-pixel accuracy.

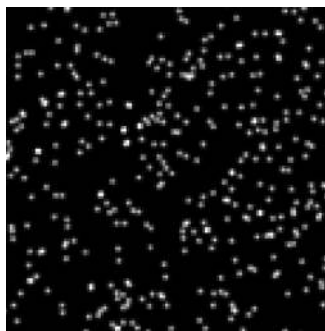
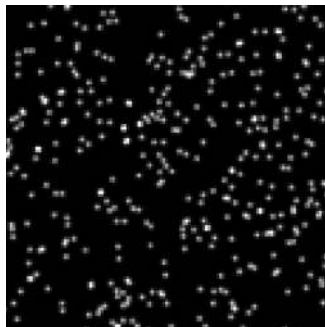
Electron Counting Requires that Electrons Don't Overlap on the Sensor



Lower beam intensity

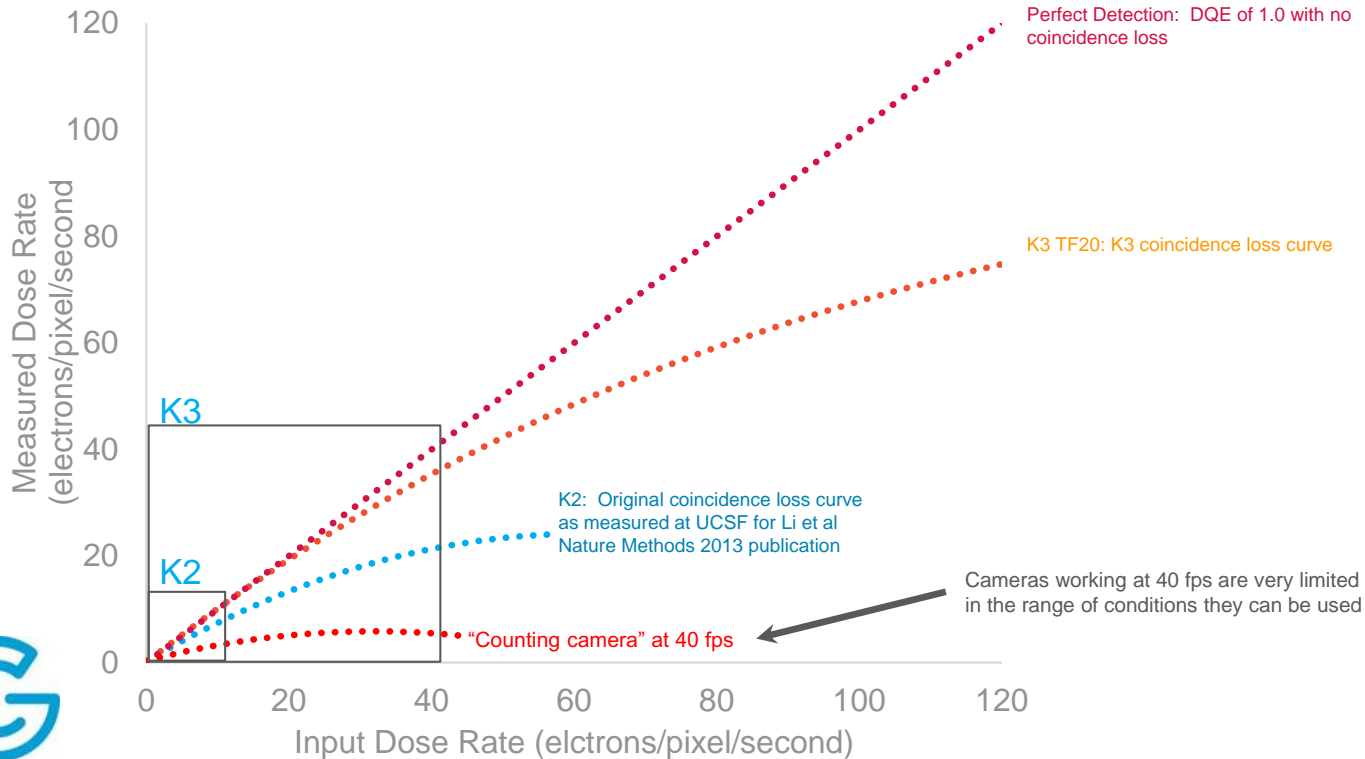


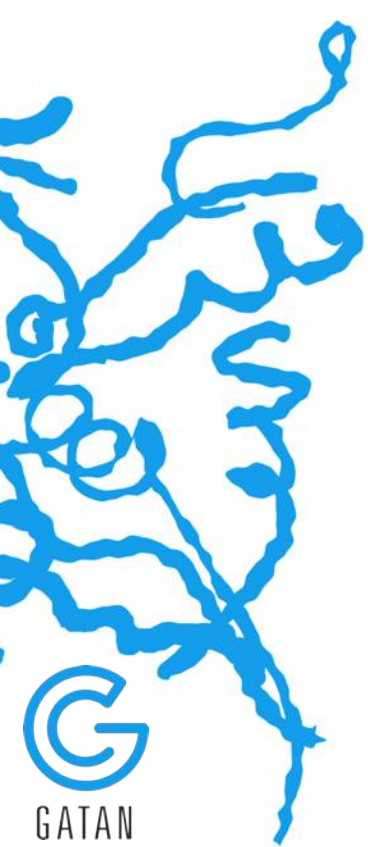
Faster frame rate



Both methods allow counting, but the effect is not equivalent!







Measuring Detector Performance

PSF, MTF, NTF and DQE?

- PSF: Point spread function
 - Blurring of a single point in the camera
- MTF: Modulation transfer function
 - PSF as a function of spatial frequency
 - Most often estimated using a “knife edge”
- NTF: Noise transfer function
 - Noise power spectrum
 - Noise as a function of spatial frequency

DQE(s)

$$= \frac{\text{SNR}_{\text{out}}(s)}{\text{SNR}_{\text{in}}(s)}$$
$$= \frac{\text{MTF}(s)^2}{\text{NPS}_{\text{out}}(s)/\text{Dose}_{\text{in}}(s)}$$

DQE Challenges

$$DQE(s)$$

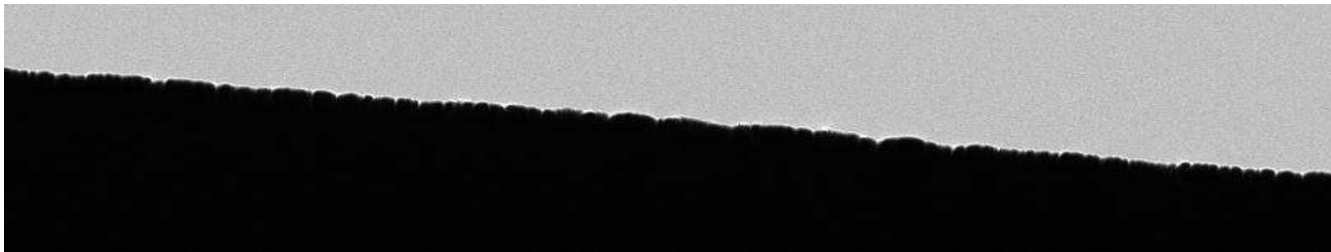
$$= \frac{SNR_{out}(s)}{SNR_{in}(s)}$$

$$= \frac{SPS_{out}(s)/SPS_{in}(s)}{NPS_{out}(s)/NPS_{in}(s)}$$

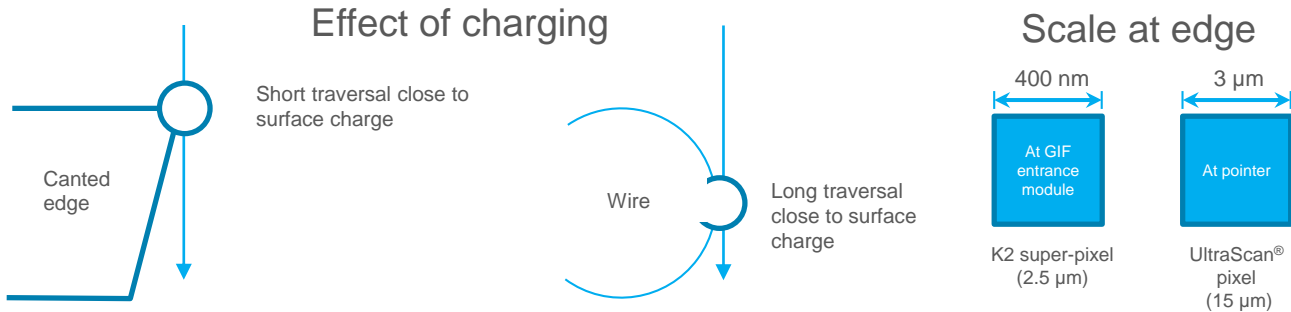
$$= \frac{MTF(s)^2}{NPS_{out}(s)/Dose_{in}(s)}$$

- Signal challenges: Edge image non-ideality
 - Charging and edge cleanliness
 - Scale
 - Edge dose
 - Motion
 - Fields
 - scatter
- Noise challenges:
 - Fixed pattern noise
 - Calibration of noise power
 - Measurement of incoming beam level
- Counting-related challenges:
 - spatial effects of coincidence loss: high-pass filtering
 - Non-linear counting due to coincidence loss – calibration.
 - background

Measuring MTF with a Physical Edge (1)



AuPd-coated and plasma cleaned edge with canted face mounted in the entrance aperture of a GIF Quantum[®] imaged on the K2 at the end of the GIF in super-resolution mode at 200 kV. (particularly bad example – not always this bad)



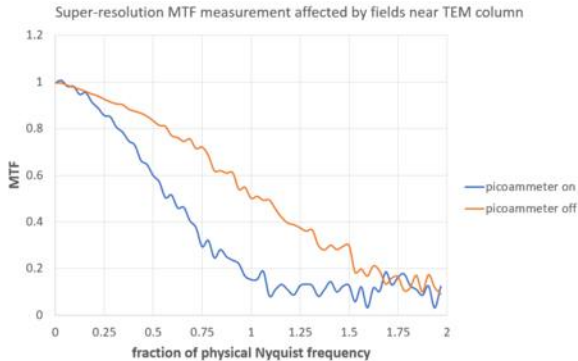
Measuring MTF with a Physical Edge (2)

Motion – edge creep

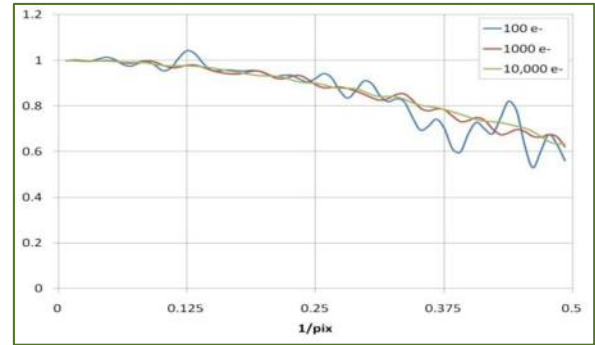


Good: difference between two 20 s edge images showing no “motion fringe”.

Motion – fields



Noise



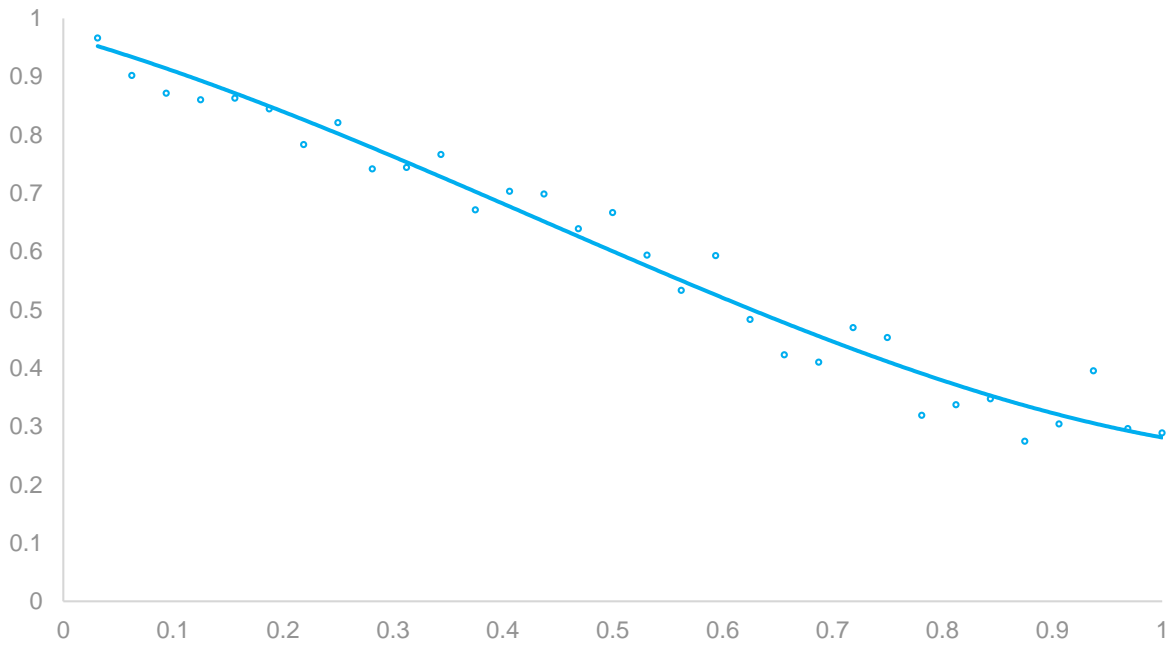
A noise-tolerant method for measuring MTF from found-object edges in a TEM, Paul Mooney, *Microscopy and Microanalysis* 15:1322-1323 CD Cambridge University Press (2009). Figure 4: Simulated MTF with various amounts of shot noise added.

At low dose rates, need long exposures to get enough dose → have to be careful about edge creep.

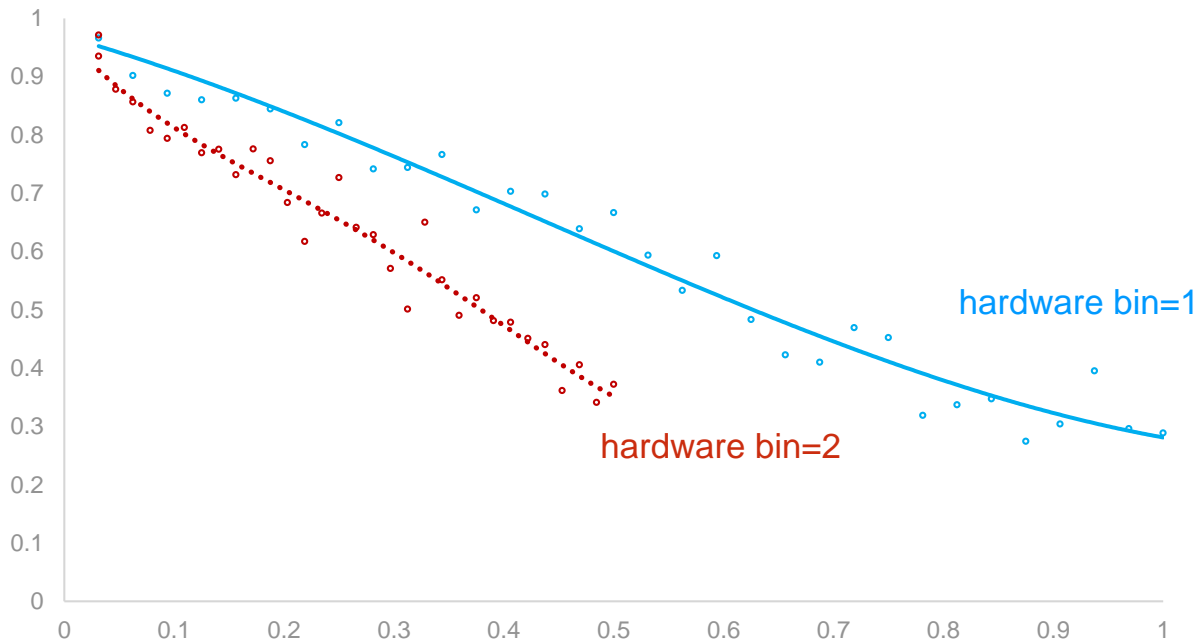
Other Things to Avoid with DQE Measurements

- Missing dose in a Faraday cup holder: overestimates DCE and therefore DQE (in same proportion)
- Using the TEM screen calibration
- Drifting beam current
 - Over- or under- values MTF(0) or DCE
- Leaving specimen holder inserted during MTF measurement
Charging of specimen and/or holder can move image of edge shadow.

DQE and Binning



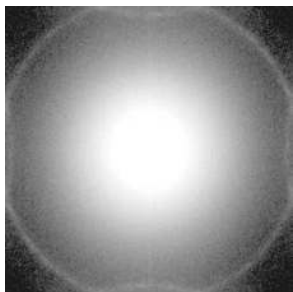
DQE and Binning



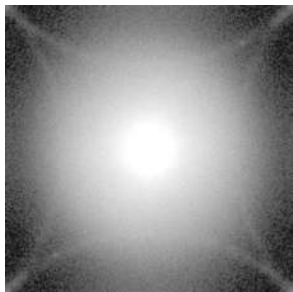
39kx



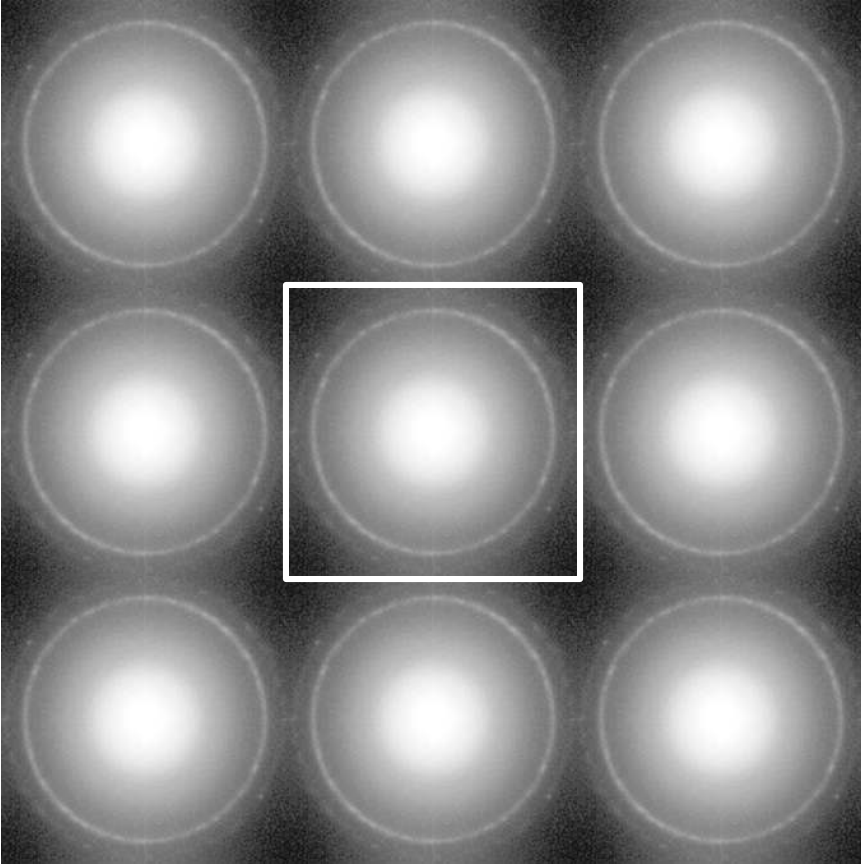
31kx



23kx



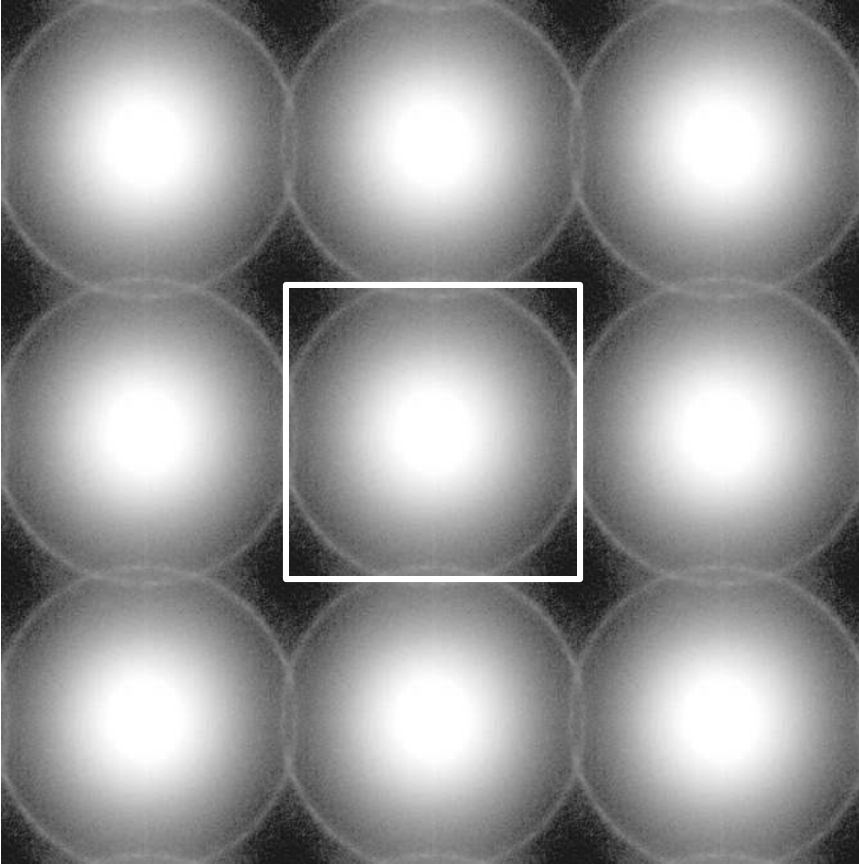
39kx



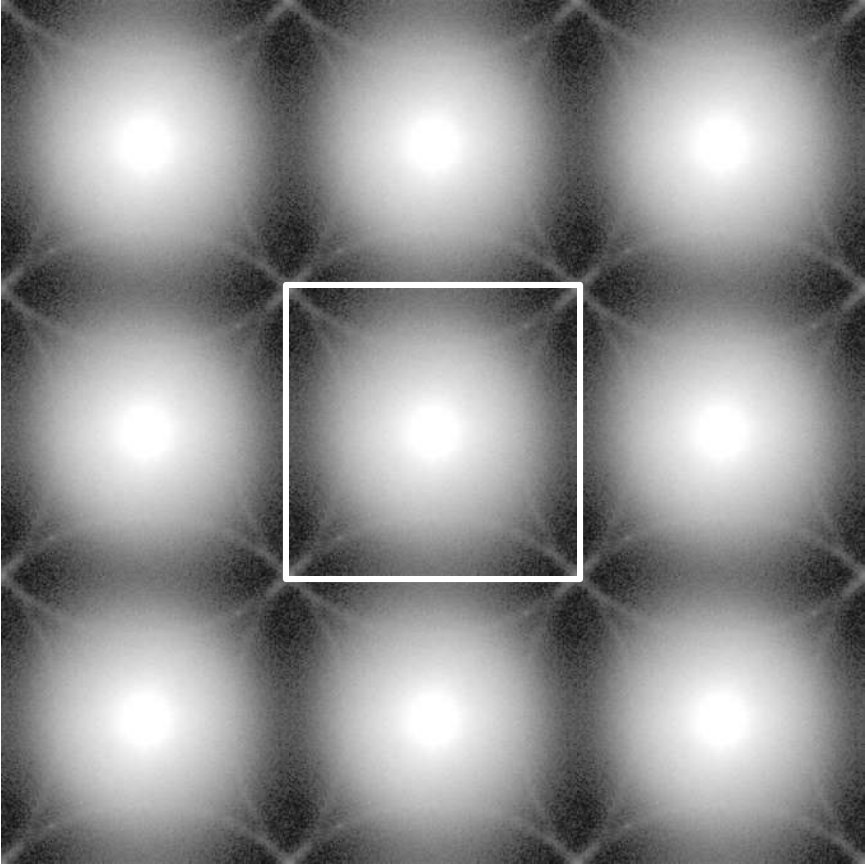
An FFT is calculated as though each image were bordered by an infinite number of neighbors

31kx

As you drop the magnification, the information from one region begins to show up in the neighboring region

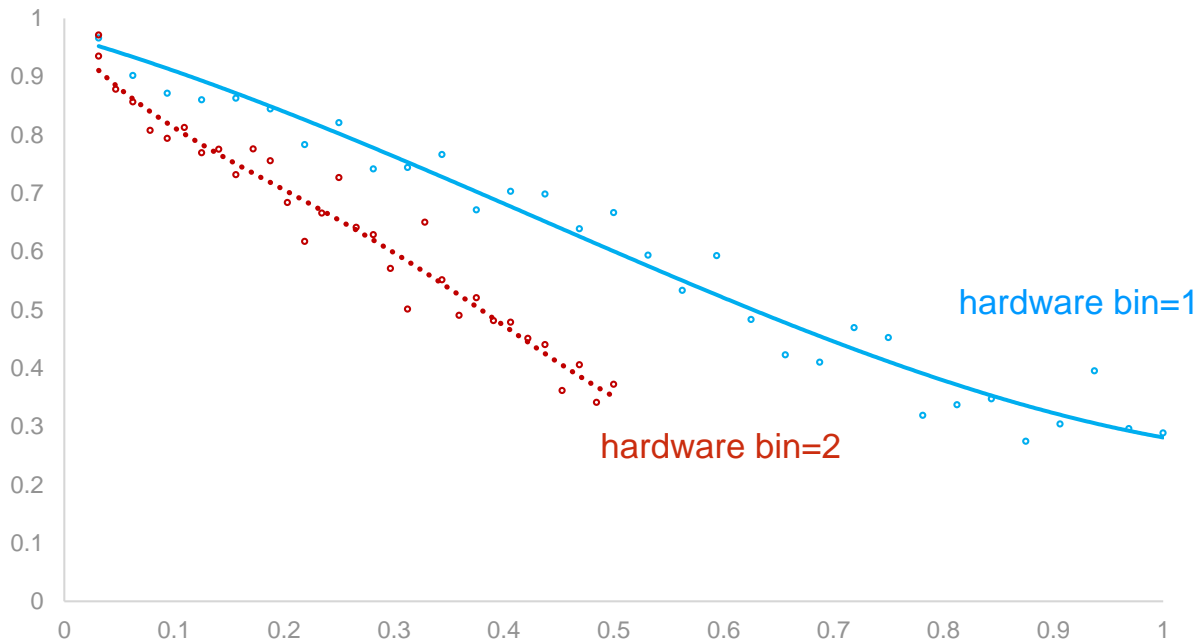


23kx

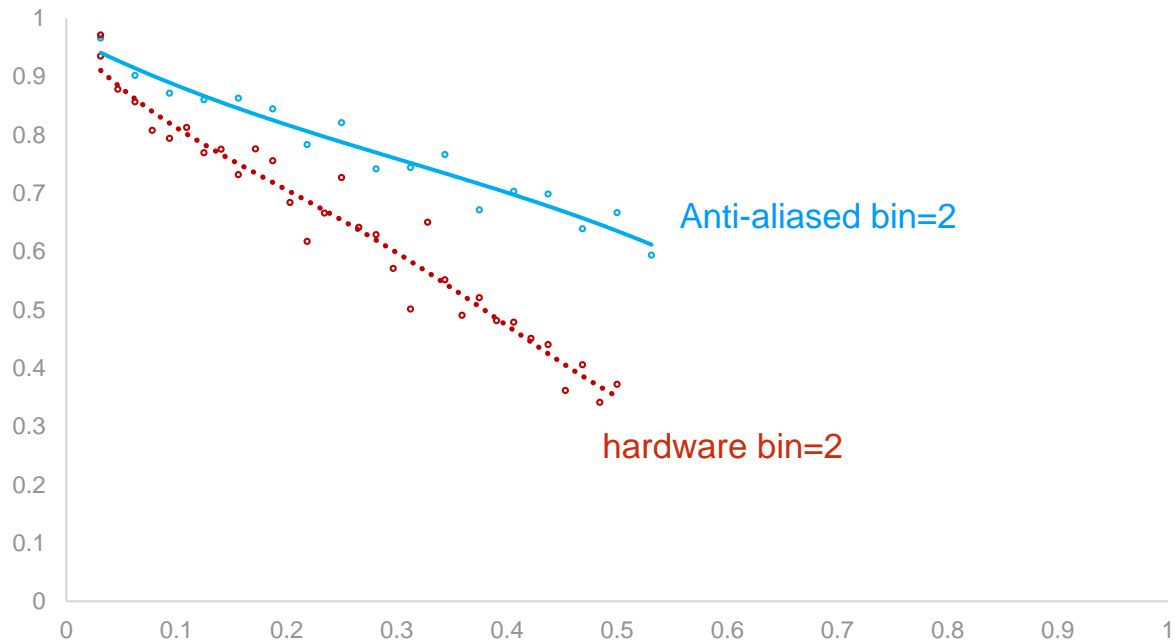


It becomes very obvious with a strong signal at low magnification

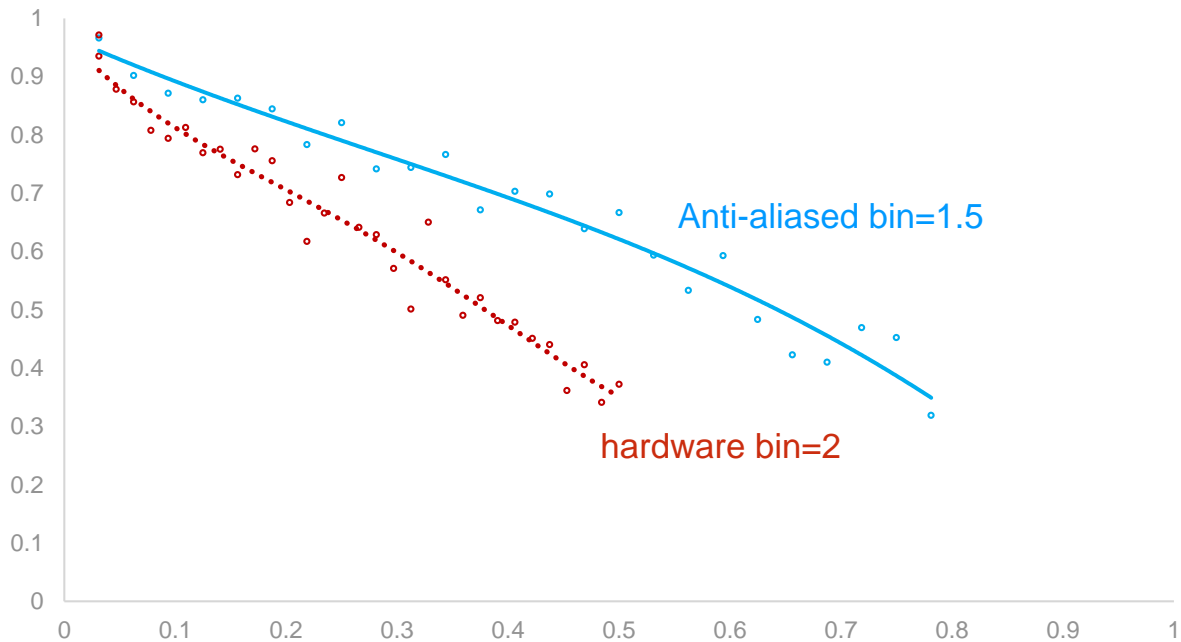
DQE and Binning



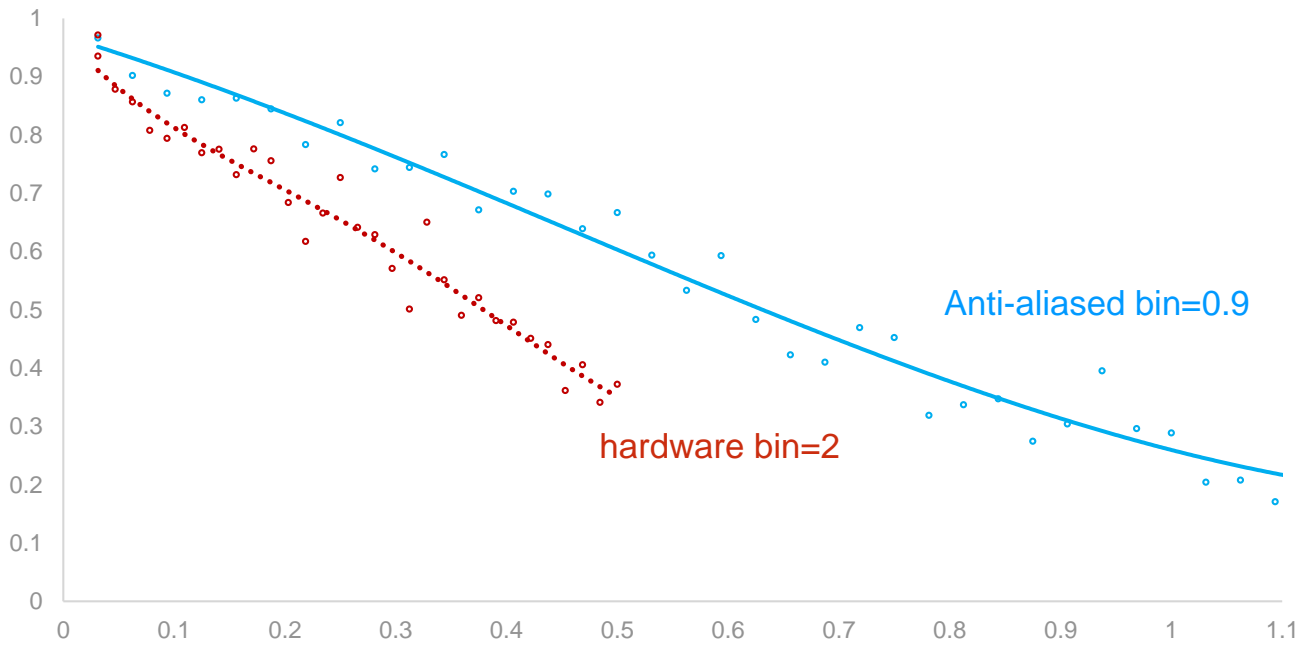
DQE and Binning



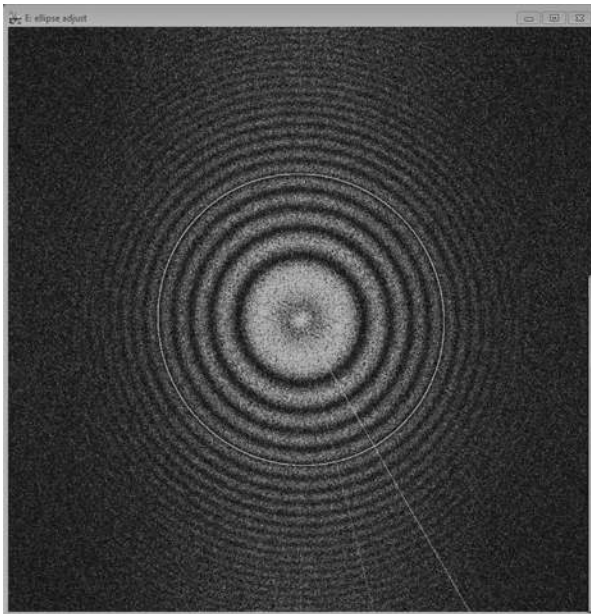
DQE and Binning



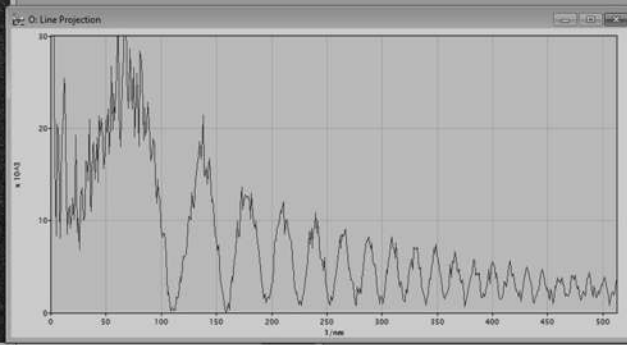
DQE and Binning

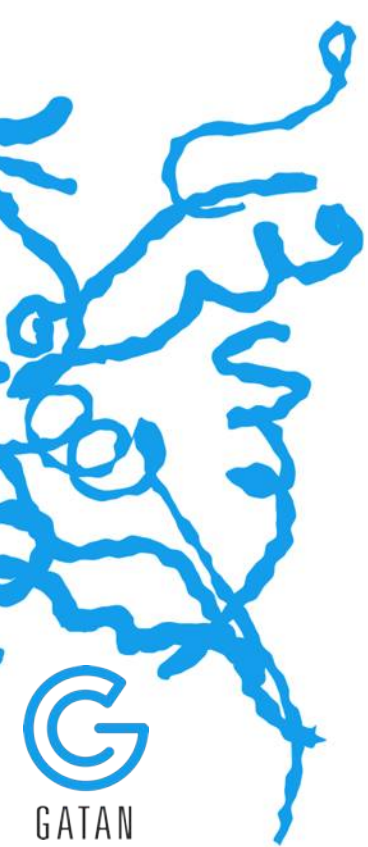


Measuring Image Performance Using Thon Rings



Thon rings are an indicator of performance. However, they are a system test and really hard to compare quantitatively.

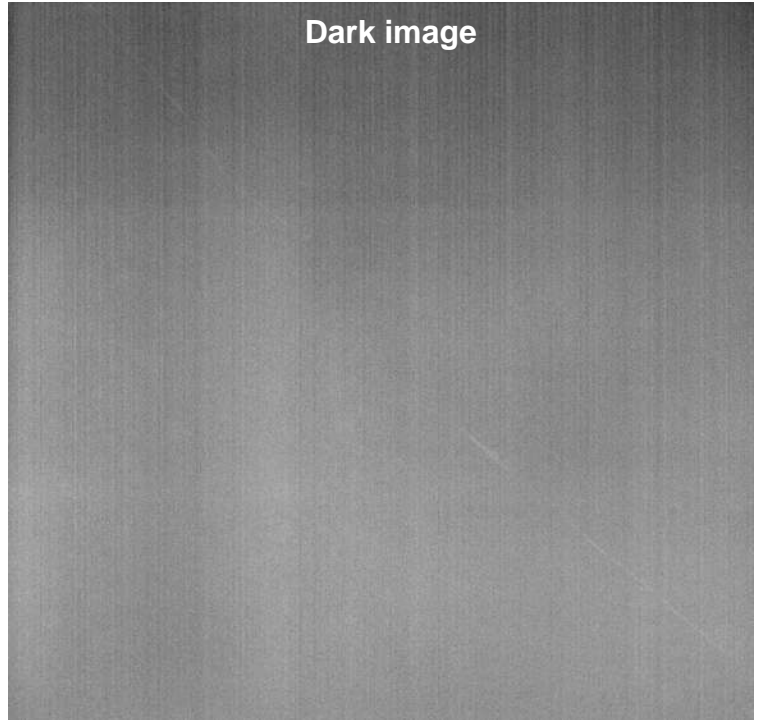




Practical Considerations in Data Collection

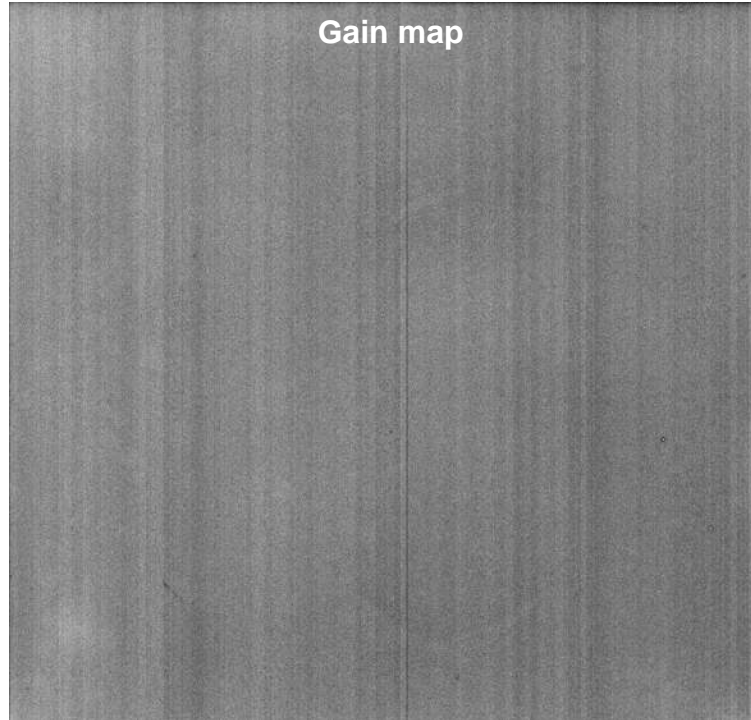
Dark Subtraction

- Removes the noise baseline from the image
- New dark references are often taken once a day



Gain Correction

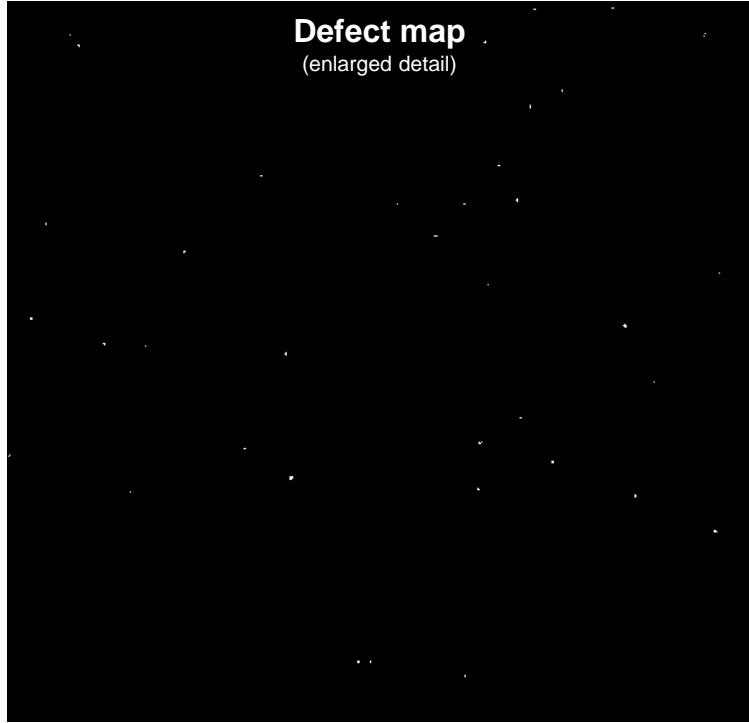
- Gain correction normalizes the response of each pixel to an electron
- This is why images are often floating point values
- In K3 we are allowing integer gain normalization
 - Each electron is 32 counts
- Usually collected once per week



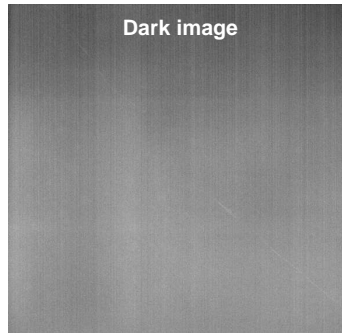
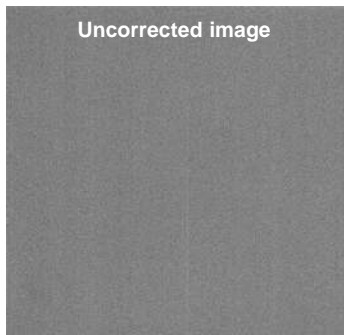
Defect Correction

- Removes poorly performing pixels
 - Hot
 - Dark
 - Unstable
- Defect pixels contribute to fixed pattern noise
- Usually updated with Gain Reference

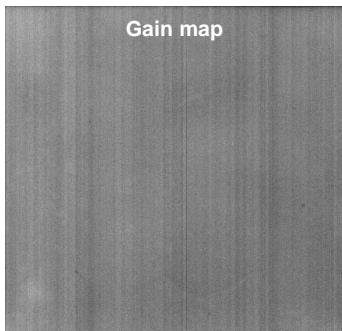
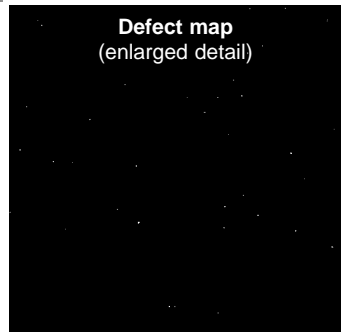
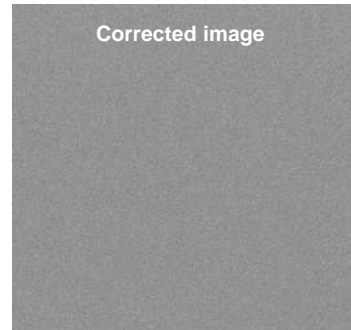
Defect map
(enlarged detail)



Typical Gain Correction Scheme

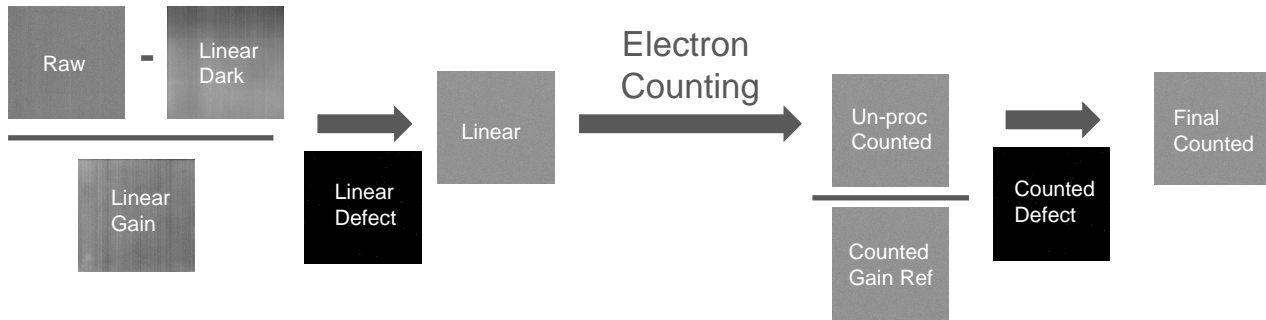


-

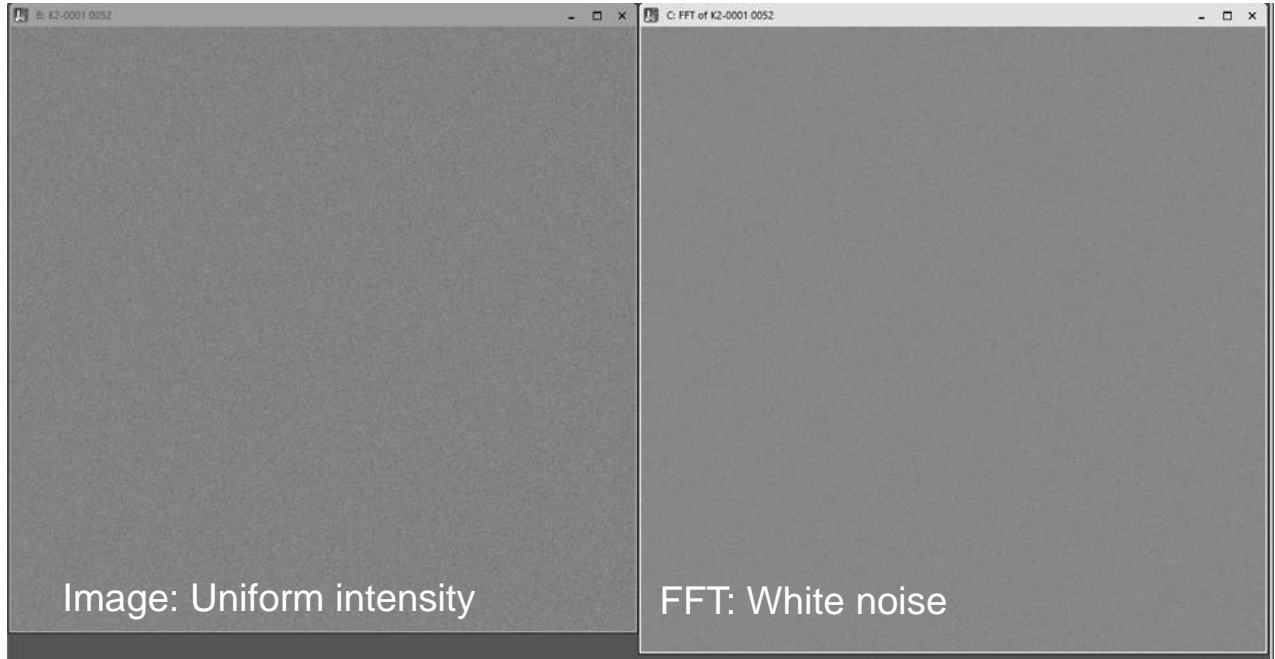


Counted Gain Correction Scheme

Linear Image Correction $\xrightarrow{\text{Electron Counting}}$ Counted Image Correction



Checking the Quality of Image Correction



Measurement of Fixed Pattern Noise (FPN)

Uniform illumination

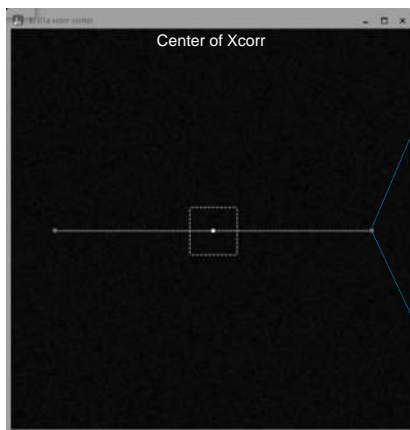
Common defects, dark image and gain image

Frame rate = 75 fr/s, (0.0133156 s/fr), all images.

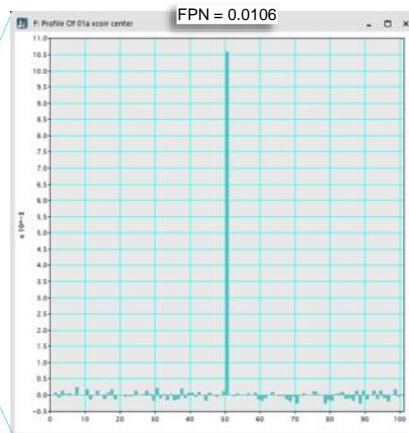
Total dose = **14 e/pix**, all images



Uniform A \otimes Uniform B

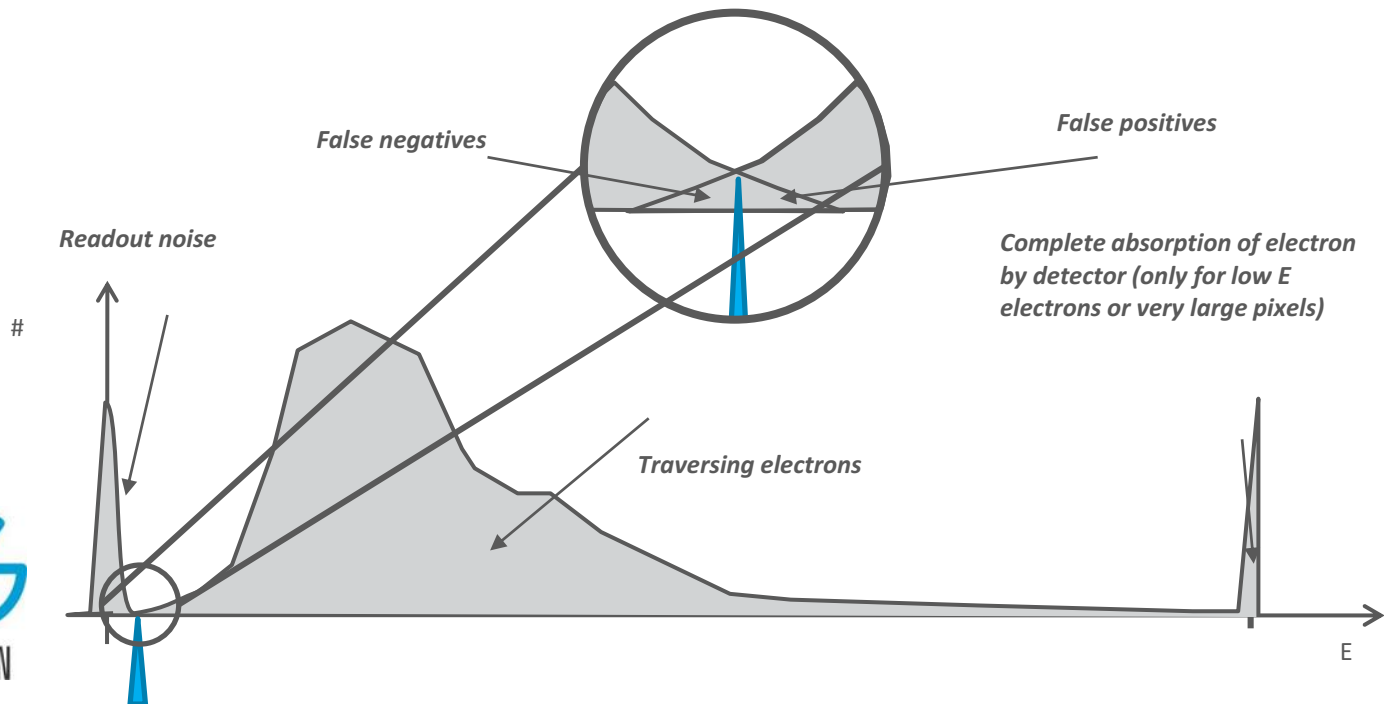


Cross-correlation map



FPN = peak pixel value

Improved Noise Also Allows us to Improve Electron Countability



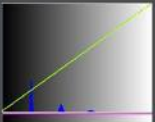
Microscope Display

Image Status

Image D
Type: Real 4
Size: 3710 x 3838 x 20

Zoom: 0.239084
 Display calibrated units

Display Control



AutoSurvey

50 50 50

Control

Slice

Slice: 0

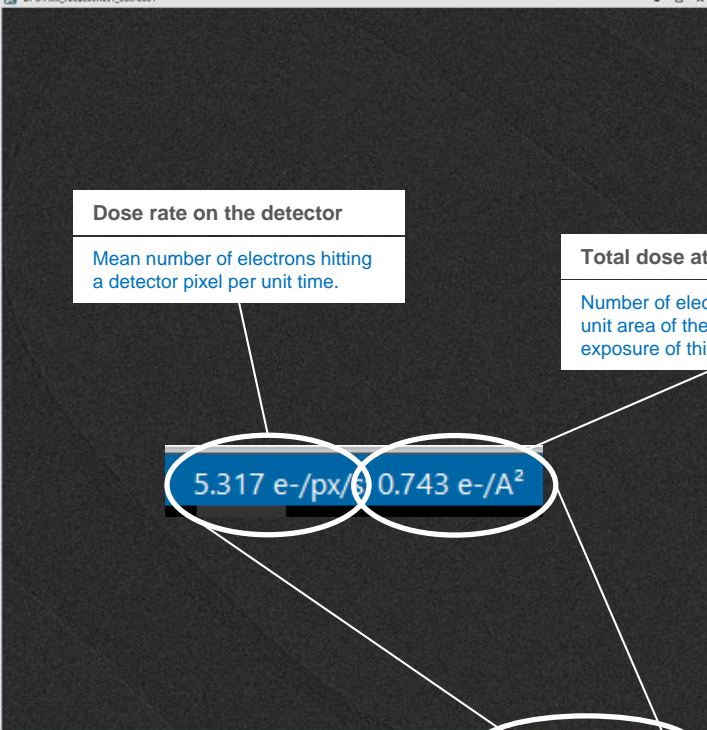
Width: 1/20

Display Center

Image Info

VIEW x

D: C-Film_focusSeries1_30K-0001



Dose rate on the detector

Mean number of electrons hitting a detector pixel per unit time.

Total dose at the sample

Number of electrons that traverse a unit area of the sample during the exposure of this image frame.

5.317 e-/px/s 0.743 e-/A²

5.317 e-/px/s; 0.743 e-/A²

Technique Manager

Technique Manager Latitude Tasks Output

TEM Imaging

K2-0001 Camera

Linear Counted Super

View Exposure (s): 0.2

Capture Exposure (s): 0.8 Auto save

Dose Frac Exposure (s): 2.0 Auto save
Frame (s): 0.25

Auto Tune

Montage

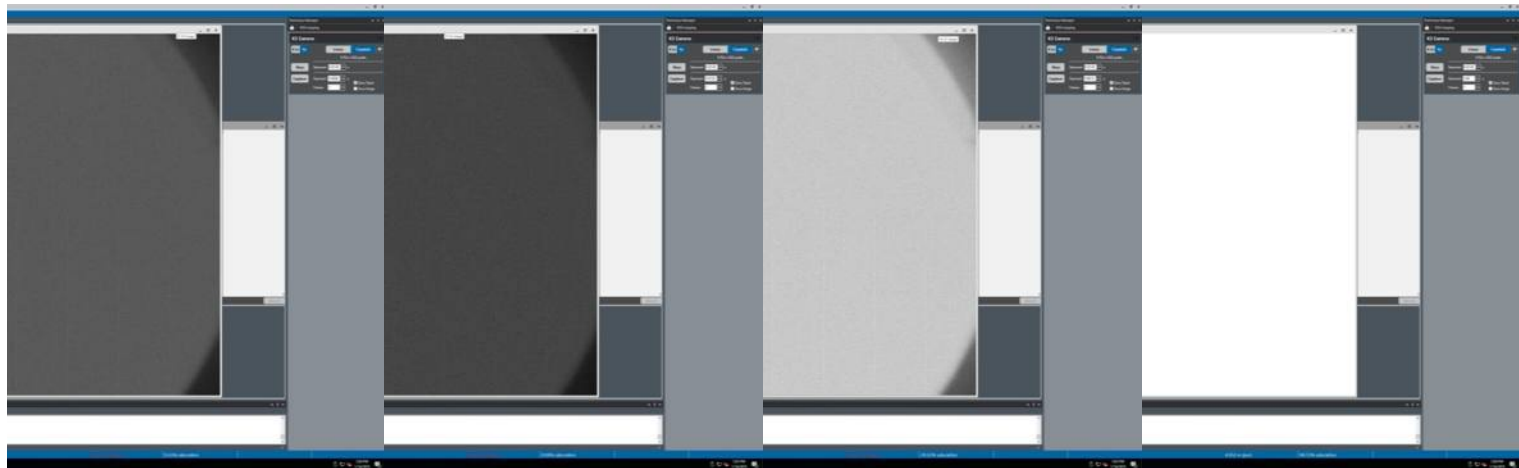
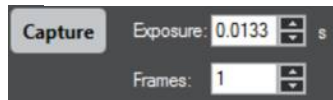
HD Video Setup

HD Video

Keeping track of Pixel Saturation in K3

At 8-bit/pixel, gain-corrected data saturates with a value of 255.

The saturation monitor reports the percentage of pixels that have reached saturation in a single frame.



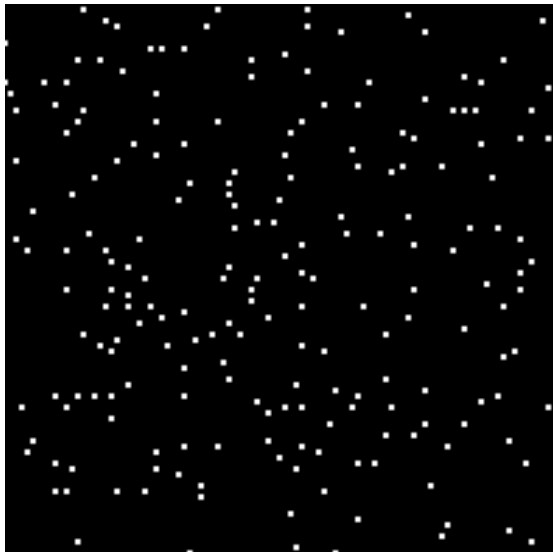
0.00% saturation

0.33% saturation

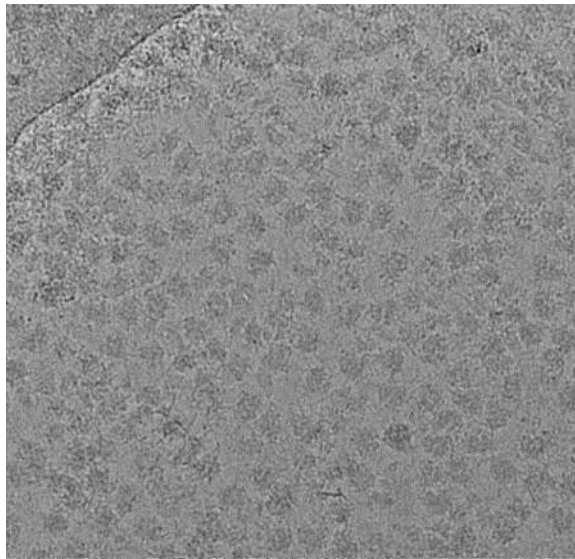
29.32% saturation

99.72% saturation

How Frame Alignment Works

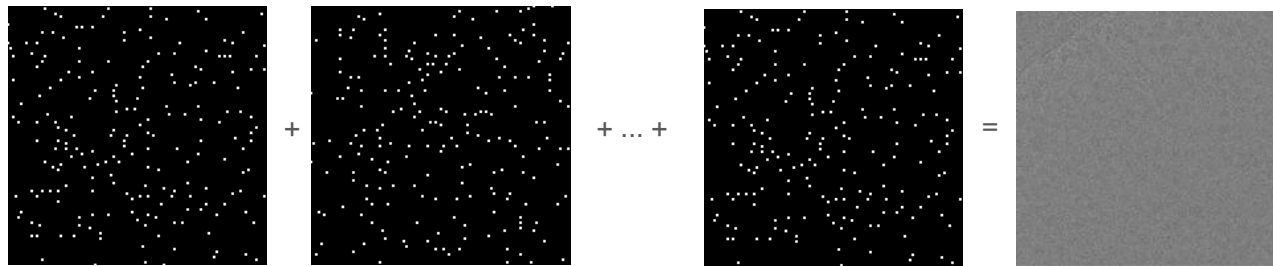


Raw counted frame

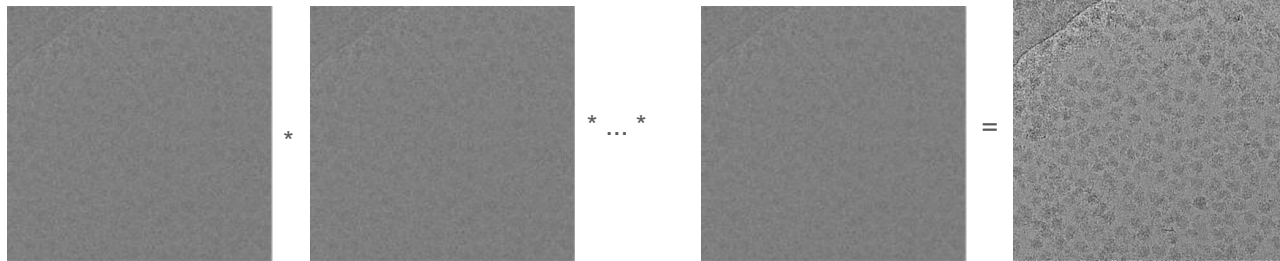


Final aligned image

Raw counted frames are summed



1 sub-frame



Sub-frames are aligned and summed

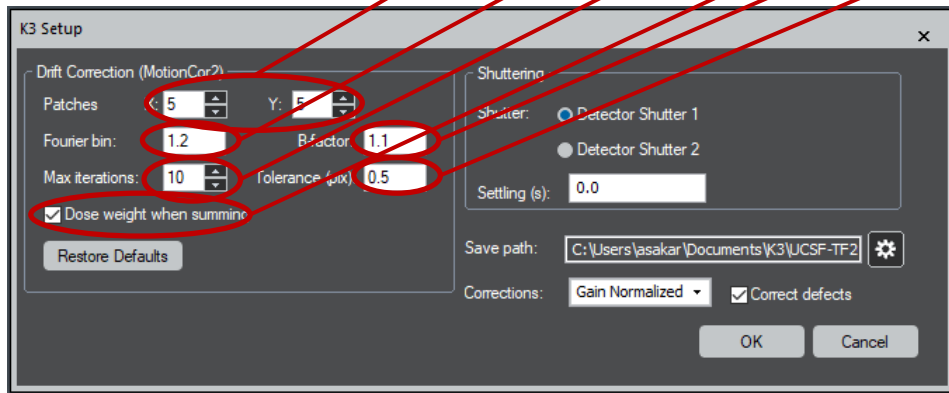
1 final image

	Sensor Frame Rate	Dose Rate	Counted Frame	Sub-frame	Summed/Aligned Frame
Other	40	0.8 e/pix/s	0.025 s	1 s (1 fps)	100 s
K2	400	8 e/pix/s	0.0025 s	0.1 s (10 fps)	10 s
K3	1500	30 e/pix/s	0.00066 s	0.027 s (37 fps)	2.7 s



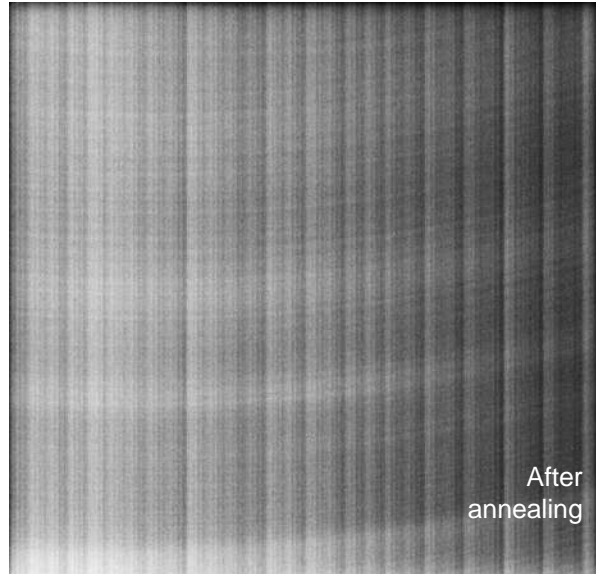
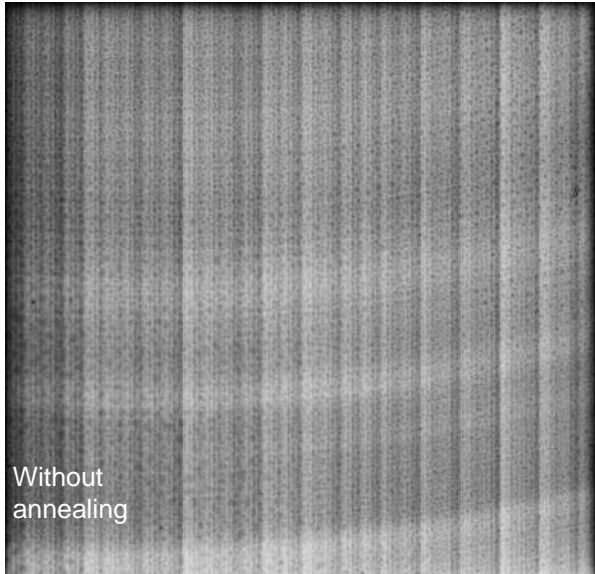
MotionCor2 on the K3

MotionCor2 -InMrc Stack.mrc -OutMrc CorrectedSum.mrc -Patch 5 5 -FtBin 1.2 -Iter 10 -FmDose 1.2 -bft 1.1 -Tol 0.5

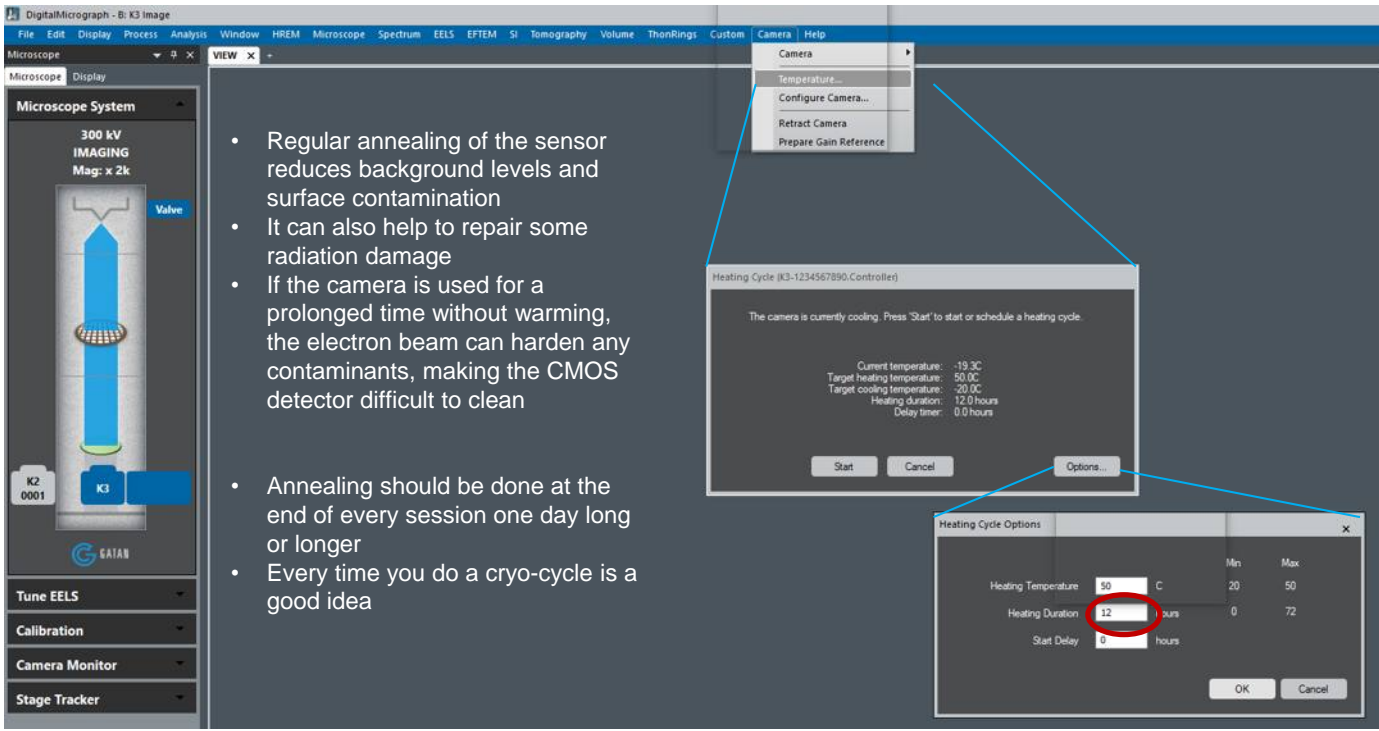


Annealing Prevents Contamination Buildup

- A cold sensor is essentially a vacuum pump. Contamination builds up on its cold surface and, if left unchecked over prolonged times, will accumulate to the point of degrade data quality
- Severe contamination may even become evident on the gain reference images, as in the example below of a K2 sensor



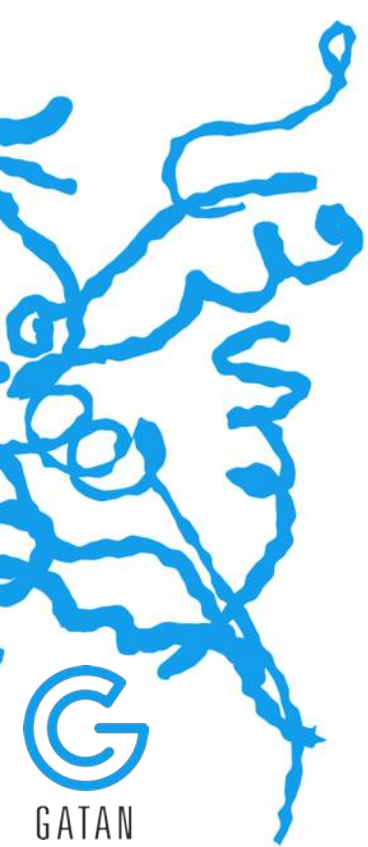
Camera Heating/Annealing



The screenshot shows the DigitalMicrograph interface. On the left is the 'Microscope System' panel with a 300 kV IMAGING Mag: x 2k and a GATAN logo. The 'Camera' menu is open, showing options: Temperature..., Configure Camera..., Retract Camera, and Prepare Gain Reference. A 'Heating Cycle (K3-1234567890.Controller)' dialog box is displayed, showing current temperature (-19.3C), target heating temperature (50.0C), target cooling temperature (-20.0C), heating duration (12.0 hours), and delay timer (0.0 hours). The 'Options...' button is highlighted. A 'Heating Cycle Options' dialog box is also shown, with 'Heating Temperature' set to 50 C, 'Heating Duration' set to 12 hours (circled in red), and 'Start Delay' set to 0 hours. The 'OK' and 'Cancel' buttons are visible at the bottom.

- Regular annealing of the sensor reduces background levels and surface contamination
- It can also help to repair some radiation damage
- If the camera is used for a prolonged time without warming, the electron beam can harden any contaminants, making the CMOS detector difficult to clean
- Annealing should be done at the end of every session one day long or longer
- Every time you do a cryo-cycle is a good idea





Future Directions for Electron Detection

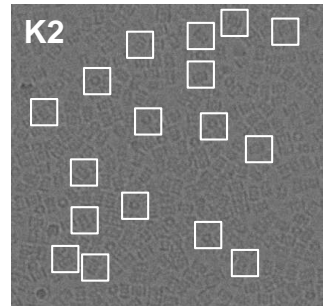
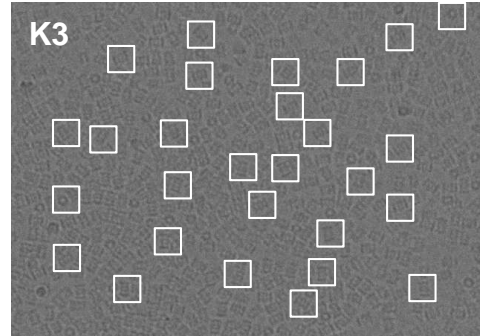
Throughput is Going to be Critical

- We should be aiming to collect enough data in a few hours
- K3 + Latitude + Titan Krios



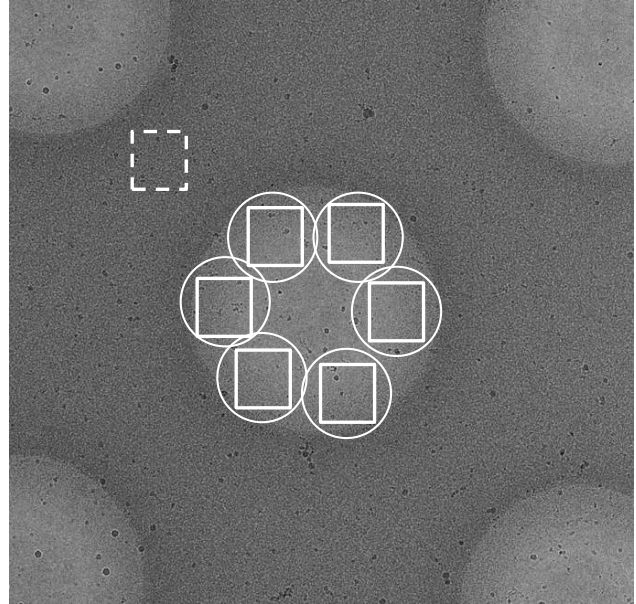
Improving Throughput: Larger Sensors

- One chance to expose a specimen area
- If the pixel quality is high, larger sensors reduce the number of images needed



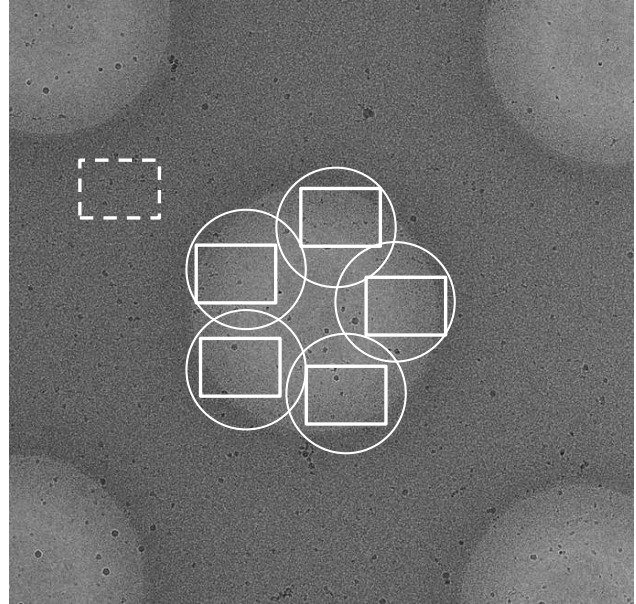
Improving Throughput: Faster Sensors

- Reduce exposure times during counting
 - Exposure times: 100 s to 10 s to 1 s
- Reduce time for non-data images during automation
 - Focusing
 - Centering



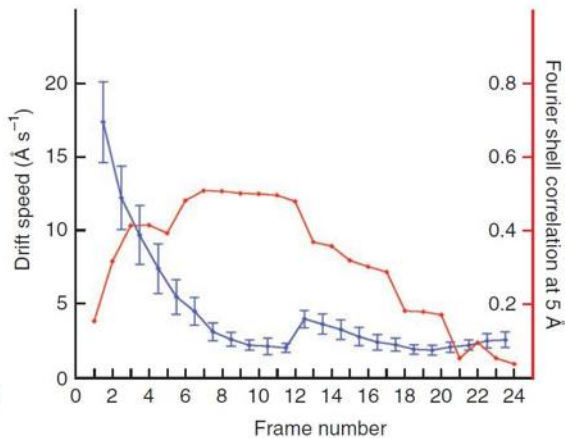
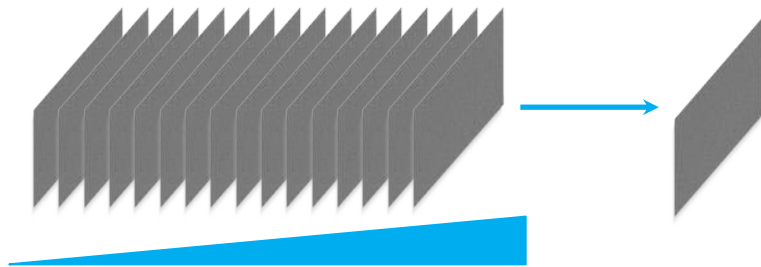
Improving Throughput

- Reducing exposure time and increasing image size gives you the biggest benefit
- K2: 6 images x 10 s = 60 s
- K3: 5 images x 2.5 s = 12.5 s
- K3: area is 25% larger



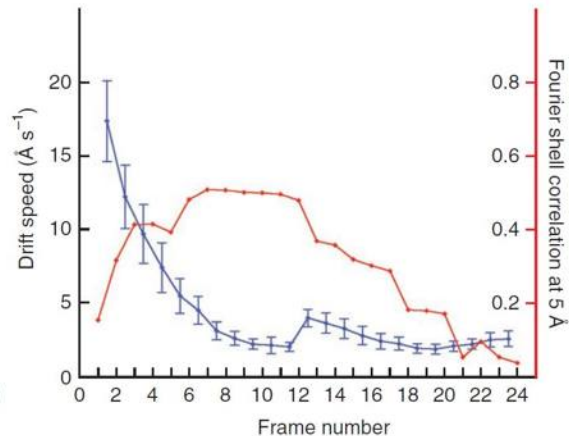
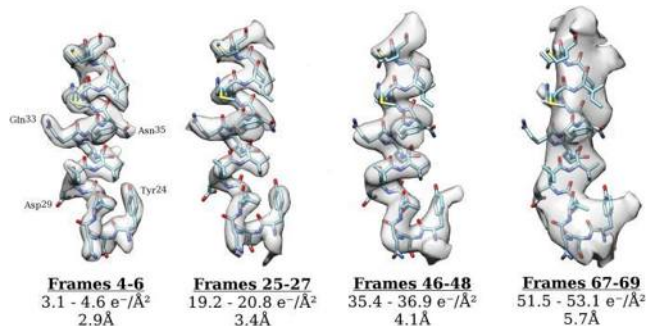
Better Data Through Motion Correction

- Sample damage increases during the exposure
- The first frames have the least damage but the most drift



Better Data Through Motion Correction

- Sample damage increases during the exposure
- The first frames have the least damage but the most drift
- Today the first 2 –3 frames are excluded
- The K3 should be fast enough to let us use frames 1 – 3 !



Thank You

